

Case 9/900165  
U.S.P.T.O.

Subclass	Class	ISSUE CLASSIFICATION

PATENT NUMBER

**U.S. UTILITY Patent Application**

~~5C3~~  
~~807~~

M.S.	O.I.P.E.	PATENT DATE
<i>[Signature]</i> SCANNED	TR. O.A. <i>[Signature]</i>	

APPLICATION NO.	CONT/PRIOR	CLASS 716 700	SUBCLASS 121	ART UNIT 2825 2125	EXAMINER BAHTA
09/900165	F				

Neal Kuo

**Method and system for determining the best integral process path to process semiconductor products to improve yield**

PTO-2040  
12/99

# Best Available Copy

TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.				NOTICE OF ALLOWANCE MAILED	
	(Assistant Examiner) _____ (Date)				
<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent No. _____ _____ _____				ISSUE FEE	
	(Primary Examiner) _____ (Date)			Amount Due	Date Paid
<input type="checkbox"/> The terminal ____ months of this patent have been disclaimed.				ISSUE BATCH NUMBER	
	(Legal Instruments Examiner) _____ (Date)				

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